

**RT-level identification of potentially testable initialization faults**

Raik, Jaan; Fujiwara, Hideo; Krivenko, Anna The Ninth IEEE Workshop on RTL and High Level Testing (WRTL T 2008), Sapporo, Japan 2008 / [6] p [https://www.researchgate.net/publication/234032548\\_RT-level\\_identification\\_of\\_potentially\\_testable\\_initialization\\_faults](https://www.researchgate.net/publication/234032548_RT-level_identification_of_potentially_testable_initialization_faults)